TOLUBINSKIY, V.I., doktor tekhn.nauk, prof.; LECKIY, V.M., kand.tekhn.nauk

Thermal and aerodynamic characteristics of two types of heating surfaces of regenerative air heaters. Energomashinostroenie 9 no.8:40-42 Ag '63. (MIRA 16:8)

(Boilers)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

TOLUBINSKIY, V.I., otv. red.; FEDOSFYEV, V.A., doktor fiz.mat. nauk, zam. otv. red.; DORFMAN, A.Sh., kand. tekhn.
nauk, red.; DUSHCHENKO, V.P., kand. fiz.-mat. nauk,
red.; DYBAN, Ye.P., kand. tekhn. nauk, red.; KREMNEV,
0.A., doktor tekhn. nauk, red.; NAZARCHUK, M.M., kand.
tekhn. nauk, red.; ORNATSKIY, A.P., kand. tekhn.nauk,
red.; PAVLOVICH, V.P., doktor tekhn. nauk, red.;
SHVETS, I.T., kand. tekhn. nauk, red.; SHCHEGOLEV, G.M.,
kand. tekhn. nauk, red.; SHCHERBAN', A.N., akademik,
red.; SYTNIK, N.K., red.

此首号字符引包 PDE 医巴拉尼亚亚维森 生物的 医物种类的 经经验 经营产品证

[Thermophysics and heat engineering] Teplofizika i teplotekhnika. Kiev, Naukova dumka, 1964. 339 p.

(MIRA 18:1)

1. Akademiya nauk URSR, Kiev. Instytut tekhnichnoy teplofizyky. 2. Institut tekhnicheskoy teplofiziki AN Ukr.SSR, Kiev (for Dorfman, Dyban, Nazarchuk, Tolubinskiy, Shchegolev). 3. Kiyevskiy tekhnologicheskiy institut pishchevoy promyshlennosti (for Dushchenko, Pavlovich).

4. Kivevskiy politekhnicheskiy institut (for Ornatskiy).

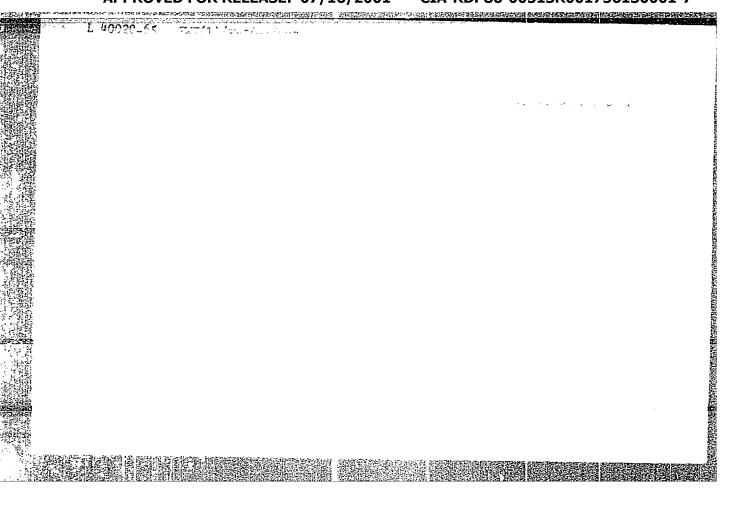
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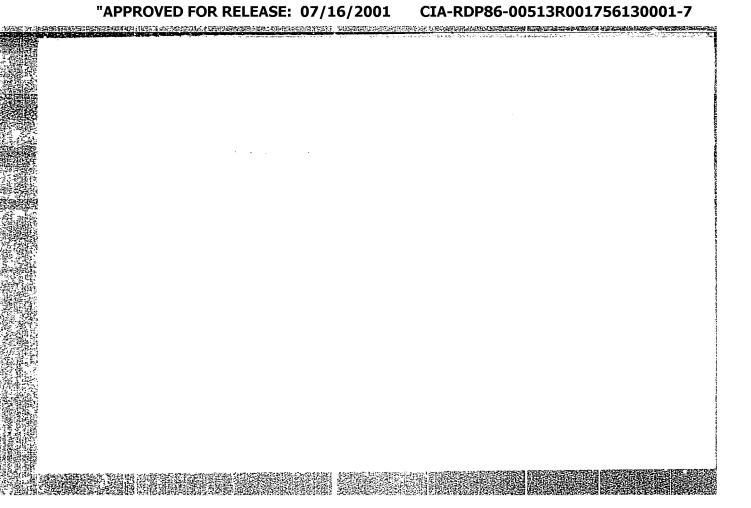
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TOLUBINSKIY, V.I.-- (continued). Card 2.

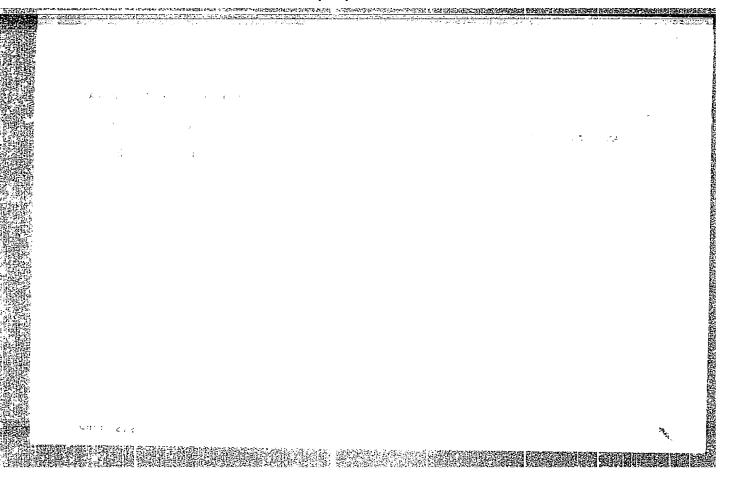
5. Odesskiy universitet (for Fedoseyev). 6. Kiyevskiy universitet (for Shvets). Akademiya nauk Ukr.SSR (for Shcherban', Shvets). 7. Chlen-korrespondent AN Ukr.SSR (for Tolubinskiy). 8. Gosudarstvennyy komitet Soveta Ministrov po koordinatsii nauchno-issledovatel'skikh rabot (for Shcherban').

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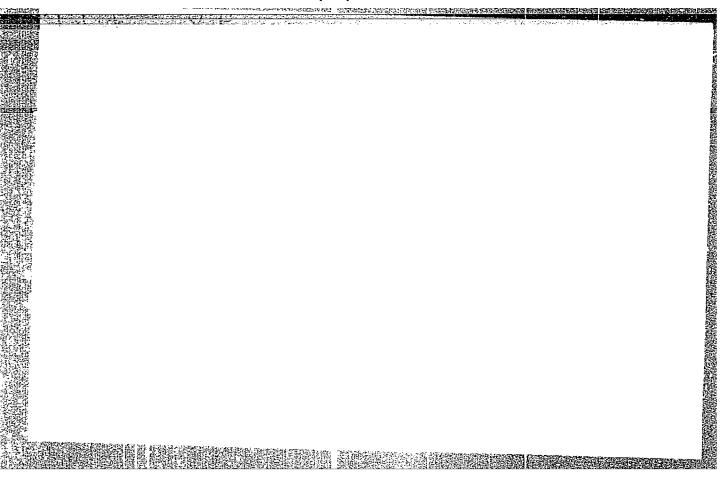


TOLUBEVA, J. K.

"The Influence of Mathylene and Sulfine Bridges Between Flenclic Rings on the Tanning Qualities of Synthetic Tanning Agents." Cand Tech Sci, Moscow Technological Inst of Light Industry imeni L. M. Kaganovich, 12 Oct 54. (VM, 30 Sep 54)

SO: Sum 432, 29 Mar 55

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"



- 	TOLUBINSKAYA, L.F.
;	Investigating heat emission during the heating of hydrocarbon gases. Trudy Inst. isp. gaza AN URSR no.4:104-113 56. (MIRA 10:12) (Hydrocarbons) (Gases) (HeatTransmission)

Integral method for solving the general heat and mass transfer problem. Dokl. AN SSSR 160 no.6:1289-1292 F '65.

(MIRA 18:2)

1. Submitted April 22, 1964.

The main battery is always on the alert. Komm. Vooruzh. Sil 45 no.8:45-47 np 165. (Mira 18:6)

<u>L 45150-66</u> ARG/EWT(d)/FBO/EWT(m)/EWP(c)/T-2/EWP(h) DE/WW

ACC NRI AP6022450 (AN) SOURCE CODE: UR/0395/66/000/007/0030/0034

AUTHOR: Tolubko, V. (Lieutenant General)

30 B

ORG: none

TITLE: Rocket technology in reliable hands [Rocket troop training]

SOURCE: Kommunist vooruzhennykh sil, no. 7, 1966, 30-34

TOPIC TAGS: training, military training, guided missile training

ABSTRACT: An important reason for the high firing accuracy of Soviet missiles is the high level of education and strategic training of Soviet missile troops. Their practical training is conducted under conditions very close to reality and takes into consideration the possibility of the enemy's use of mass-destruction means. Soviet missile troops are equipped with long-range ballistic missiles with powerful nuclear warheads developed on the basis of the newest scientific and technical achievements. Seventy-five percent of the officers in the missile troops are engineers educated in the theory of rocket engines, aerodynamics, thermodynamics, chemistry, physics, and electronics. The commanding personnel and instructors in special disciplines

Card 1/2

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L 45150-66			
ACC NR: AP6022450			
have had a pedagogical education and use individual training methods. The author recommends reports and lectures as well as military technical information meetings to be followed by discussions related to some specific field of rocketry, thus raising the interest of participants and their level of knowledge. The interchangeability of responsibilities and skills within crews is recommended. However, only those who responsibilities and skills within crews is recommended. However, only those who have completely mastered their own specialty can successfully undertake learning others.			
SUB CODE: 15/ SUBM DATE: none/			
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Card 2/2 augu			

Honorable mission. Starsh.—serzh. no.5:9 My '62. (MIRA 15:6)

1. Zamestitel' glavnokomanduyushchego Rakitnymi voyskami.

(Rockets (Ordnance))

CIA-RDP86-00513R001756130001-7 "APPROVED FOR RELEASE: 07/16/2001

SOURCE CODE: UR/9008/66/000/269/0001/0001 ACC NR. AN6034954

AUTHOR: Tolubko, V. E. (Colonel general; First deputy commander in chief of strategic rocket forces)

ORO: none

TITLE: Powerful, invincible force [Soviet missile forces discussed]

SOURCE: Krasnaya zvezda, no. 269, 19 Nov 66, p. 1, cols 4-7

TOPIC TAGS: antitank missile, tactical missile, ballistic missile, solid propellent missile, missile performance, mobile missile site

ABSTRACT: This article states that at the present time the rocket forces are the primary branch of the Soviet armed forces with the ability to strike strategic military targets. Soviet military forces are now receiving an entire complex of strategic weapons, including solidfuel missiles equipped with mobile launchers; these have greater maneuverability, virtual invulnerability, and high reliability. Rocket forces and army artillery units are presently receiving missile weapons with nuclear warheads, new types of artillery, tactical rockets, and a guided antitank missile.

SUB CODE: 15, 16, 19/ SUBM DATE: none

Card 1/1

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

ASTASHENKOV, Petr Timofeyevich, inzh,-polkovnik; TOLUHKO, V.F.,
general-polkovnik, red.; KADER, Ya.M., red.

[Soviet rocket troops] Sovetskie raketnye voiska. Moskva,
Voenizdat, 1964. 231 p.

1. Pervyy zamestitel' Glavnokomanduyushchego Raketnymi
voyskami strategicheskogo naznacheniya (for Tolubko).

KOCHANOVSKIY, N. Ya., kand.tekhn.nauk, red.; GROMYKO, L.G., red.; YEGOROVA, I.A., red.; TERENT' YEV, Yu.Ya., red.; TOLUB' YEVA, Ye.P., red.; ARIFMETCHIKOV, F.V., red.; RODIONOV, Yu.I., red.; BALASHOV, V.I., tekhn.red.; BURLAKOVA, O.Z., tekhn.red.

[Welding equipment; annotated catalog] Svarochnoe oborudovanie; katalog-spravochnik. Moskva. TSentr.in-t nauchno-tekhn. informatsii elektrotekhn.promyshl. i priborostroeniia, 1960. (MIRA 14:4) 359 p.

1. Vsesoyuznyy nauchno-issledovatel skiy institut elektrosvarochnogo oborudovaniya (for Gromyko, Yegorova, Terent'yev,
Tolub'yeva). 2. Gosudarstvennyy nauchno-tekhnicheskiy komitet
(for Arifmetchikov). 3. TSentral'nyy institut nauchno-tekhnicheskoy informatsii elektrotekhnicheskoy promyshlennosti i
priborostroyeniya (for Rodionov).

(Welding-Equipment and supplies)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

ON THE PROPERTY OF THE PROPERT

[Welding equipment; catalog-handbook] Spravochnoe oborudovanie; katalog-spravochnik. Moskva, TSentr. in-t nauchno-tekhn. informatsii elektrotekhn.promyshl. i priborostroeniia, 1960. (MIRA 13:12)

1. Vsesoyuznyy nauchno-issledovatel skiy institut elektrosvarochnogo oborudovaniya (for Gromyko). 2. Gosudarstvennyy nauchno-tekhnicheskiy komitet (for Arifmetchikov). 3. TSentral'nyy institut nauchno-tekhnicheskoy informatsii (for Rodionov).

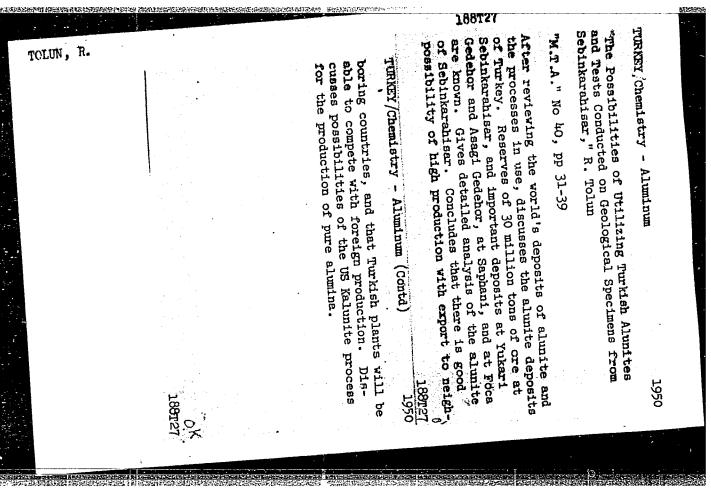
(Welding-Equipment and supplies)

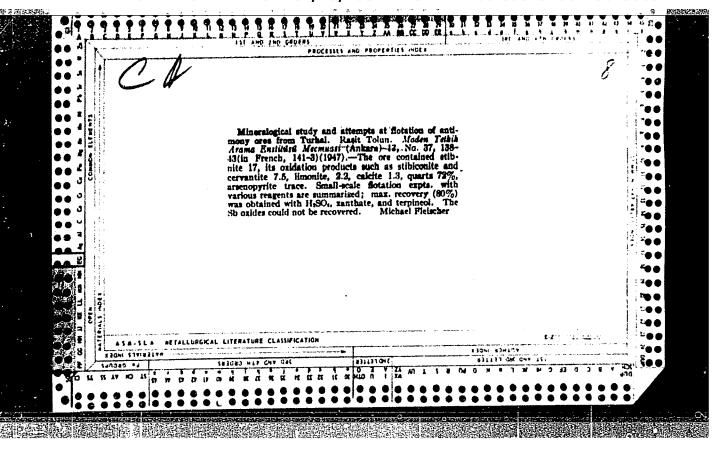
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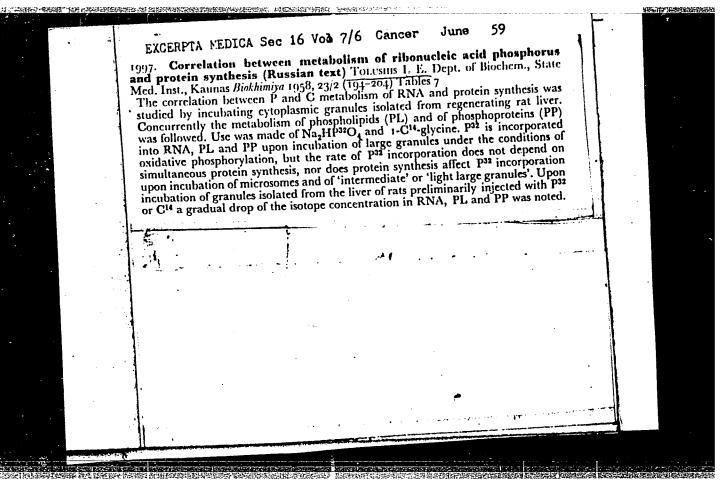
PANCHENKOV, G.M.; FOLUMACHEV, A.M.; FEDOROV, V.A.

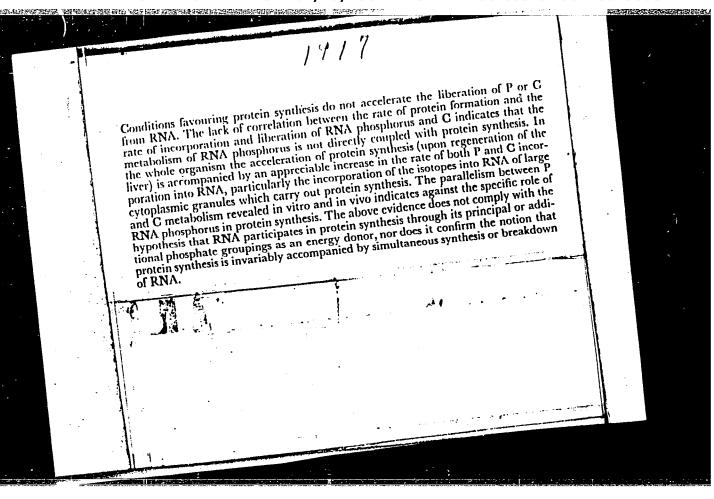
Synthetic zeolites as ion exchangers. Part 2: Equilibrium of ion exchange. Zhur.fiz.khim. 37 no.2:456-459 F '63. (MIRA 16:5)

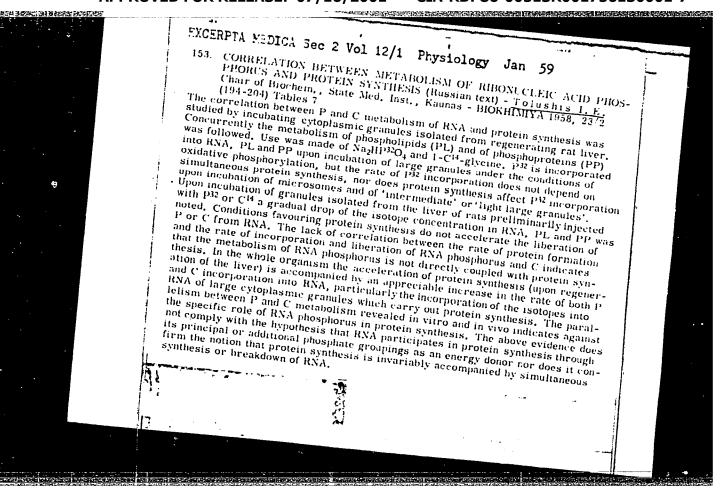
1. Moskovskiy gosudarstvennyy universitet imeni M.V.Lomonosova. (Zeolites) (Ion exchange)











TOLUTIS, V.

Dissertation: "Conditions of Formation and Properties of the Closing Layer in Systems of Thin Layers." Cand Phys-Math Sci, Vil'nyus State U, Vil'nyus, 1954. (Referativnyy Zhurnal--Fizika, Moscow, Aug 54)

SO: SUM 393, 28 Feb 1955

THE COLUMN TWO ISSUES AND THE TRANSPORTED AND

TOLUTTS, V.

SCIENCE

PERIODICAL: DARBAI. SERIJA B. TRUDY. SERIIA B. No. 2, 1958

Tolutis, V. Asymmetry of conductivity systems with multipoint contact. In Russian. p. 25.

Monthly list of East European Accessions (EEAI) LC. Vol. 8, No. 2, February 1959, Unclass.

CIA-RDP86-00513R001756130001-7 "APPROVED FOR RELEASE: 07/16/2001

TOLUTIS, V.B. [Tolutis, V.]; SHIMULITE, E.A. [Simulyte, E.] Rectifiers with a small threshold of rectification based on contact of hexagonal selenium with cadmium, gallium, indium, and thallium. Liet

ak darbai B no.2:67-81 '60.

1. Institut fiziki i matematiki Akademii nauk Litovskoy SSR. (Electric current rectifiers) (Selenium) (Indium) (Thallium) (Gallium) (Cadmium)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

h1886 5/236/62/000/001/002/007 D207/D307

26.2420.

AUTHORS:

Tolutis, V.B. and Yalatsyavichene, I.A.

TITLE:

Combined investigation of thin layers of cadmium telluride. I. Introduction. General methodological problems. Conductivity of thin layers of cadmium

telluride in strong electric fields

SCURCE:

.kademiya nauk Litovskoy SSR. Trudy. Seriya B,

no. 1(28), 1962, 17-31

UdTe is of special interest because of its high efficiency in solar energy conversion. A brief review of literature shows that the method of preparation influences strongly the structure and composition of CdTe. In the present work (reported in Parts I-V) CdTe was prepared (by V. Yasutis) by melting together (at 600°C, followed by 1000°C) spectroscopically pure Cd and 99.998% (at 600°C, followed by 1000°C) spectroscopically pure Gd and 99.998% pure Te in vacuum. This was followed by grinding the product and remelting at 1100°C (3 hours). The final product was of 99.999% Thin $(1\,\mu)$ layers of UdTe were obtained by evaporation and Card 1/2

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Combined investigation ...

deposition in vacuum on cold or heated (to 350°C) quartz and other substrates. The adhesion was good on heated substrates but poor on cold ones. The adhesion was related to the characteristic temperature dependence of the linear thermal expansion coefficient of GdTe; the room-temperature value of this coefficient, measured with a MMM-4 (MII-4) interference microscope, was found to be 6.2 x 10-6 deg-1. The combined investigation consisted of a series of measurements of various properties using the same principle. The order of measurements was carefully selected to avoid the effects of irreversible changes and most of the measurements were carried out in vacuum. The properties of GdTe layers were strongly influenced by the conditions of deposition because GdTe decomposes on evaporation into Te₂ and Gd and recombines again on the substrate. The nonlinearity of the current-voltage characteristics of GdTe layers in strong electric fields (10⁵ V/cm) was found to be principally due to heating by the fields. There are 9 figures.

ASSOCIATION:

Institut fiziki i matematiki Akademii nauk Litovskoy

SSR (Institute of Physics and Mathematics, Academy

of Sciences, LithSSR)

Card 2/2

SUBMITTED:

February 23, 1961

41887 S/236/62/000/001/003/007 D207/D307

26.2420

AUTHORS:

Tolutis, V.B. and Shimulite, Ye.A.

TITLE:

Combined investigation of thin layers of cadmium telluride. II. Electrical conductivity in weak elec-

tric fields and contact phenomena

SOURCE:

Akademiya nauk Litovskoy SSR. Trudy. Seriya B,

no. 1(28), 1962, 33-50

This paper is a continuation of the combined investigation of thin layers of cadmium telluride (see Part I). Electrical properties were measured on layers of stoichiometric composition, as well as on layers with an excess of tellurium or cadmium. The excess of tellurium was produced by heating in high vacuum, the excess of cadmium - by heating in saturated cadmium vapor or by the Vekshinskiy method. The treatment in saturated cadmium vapor was carried out by K. Valatska and V. Yasutis. The temperature dependence of the electrical conductivity was found in high vacuum using probes and the electrometer circuit. Leasurements at low temperatures were limited by the fact that the resistance rose rapidly: at -40°C the Card 1/3

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Combined investigation ...

resistance reached 10^{13} - 10^{14} ohm. The rectilinear log σ = f(1/T) characteristics (σ is the electrical conductivity and T is the temperature) were strongly altered by heating to 450°C because such heating changed the concentration of impurity centers. The hightemperature variations in the impurity-center concentration were due to cadmium which can easily leave its lattice site because of its low activation energy and small radius. The complex mechanism of carrier recombination was due to the instability of the concentration of recombination centers which were produced by secondary thermal ionization of cadmium vacancies of interstitial cadmium atoms; the interaction between volume and surface processes also affected carrier recombination. The activation energies of the impurity centers and the forbidden band width (~ 1.5 eV) of the layers agreed well with the values for monocrystals. Contact phenomena were investigated by: 1) recording current-voltage characteristics, 2) studying the potential distribution across the sample by means of It was found that a moving probe, or 3) measuring the noise level. satisfactory ohmic contacts with p-type layers were obtained using gold, silver and antimony electrodes. Gold electrodes which were Card 2/3

Combined investigation ...

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not heat-treated formed obmic contacts with n-type layers; heating destroyed the obmic nature of these contacts. Indium electrodes on n-type layers were obmic, but on p-type they had rectifying properties. The obmic nature of indium contacts on n-type layers was retained after heating; aluminum electrodes had properties similar to those of indium. The lowest contact noise was obtained with obmic indium electrodes. The contact phenomena could all be explained within the framework of the usual contact theory by taking into account the specific properties of CdTe layers. There are 10 figures and 1 table.

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of Sciences, LithSSR)

·SUBMITTED:

February 23, 1961

Card 3/3

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26. 24.30

AUTHORS:

Valatska, K.K. and Tolutis, V.B.

TITLE:

Combined investigation of thin layers of cadmium

telluride. III. Photoelectric properties

SOURCE:

Akademiya nauk Litovskoy SSR. Trudy. Seriya B,

no. 1(28), 1962, 51-62

TEXT: This paper is a continuation of the combined investigation of thin layers of cadmium telluride (see Parts I-II). Photoelectric properties were measured on layers heat-treated in vacuum (excess Te) and in Cd vapor (excess Cd). The layers deposited in vacuum on cold substrate, had low photosensitivity. After heating in vacuum or in Cd vapor photosensitivity increased due to greater grain dimensions and more perfect structure. The photoconductivity maximum at 0.03 // corresponds to the fundamental absorption edge of CdTe and is related to the volume photoconductivity. The fall of the photoconductivity in the fundamental absorption region is due to strong carrier recombination on the surface. A small

Card 1/3

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Combined investigation ...

additional photoconductivity maximum at 0.89 μ was found in the samples heat-treated in Gd vapor. The activation energy determined from the wavelength at which the photocurrent peak decreased to half its value on the long-wavelength side did not represent the forbidden band width of CdTe. This band width and its temperature dependence was found using the inflection point on the short-wavelength side of the photocurrent peak; the value of the forbidden band width was 1.53 - 1.54 eV. The temperature coefficient of the forbidden band width was -(3.1 - 3.6) x 10-4 eV/deg. The layers heat-treated in Cd vapor exhibited quite slow relaxation of the photoconductivity (the relaxation time was of the order of several minutes); the decay was hyperbolic. The steady-state photoconductivity was proportional to L , where L is the luminous flux and $\alpha = 0.5 - 1$. For the majority of samples at room temperature α = 0.5. On increasing the temperature to 100°C α approached 1; this was due to increase of the dark conductivity. By suitable heat treatment it was possible to obtain CdTe photoresistors with relatively low dark resistance (107 - 106 ohm). Acknowledgement is made to Professor P. Brazdzhyunas for reading the manuscript and Card 2/3

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Combined investigation ...

his valuable remarks. There are 7 figures and 1 table.

ASSOCIATION:

Institut fiziki i matematiki Akademii nauk Litovskoy SSR (Institute of Physics and Mathematics, Academy of Sciences, LithSSR)

SUBMITTED:

February 25, 1961

Card 3/3

CIA-RDP86-00513R001756130001-7" **APPROVED FOR RELEASE: 07/16/2001**

41890 S/236/62/000/001/006/007 D207/D307

26 2400

AUTHORS:

Kuchis, Ye.V. and Tolutis, V.B.

TITLE:

Combined investigation of thin layers of cadmium (telluride. V. Some methodological problems in investigation of the Hall effect in thin high-resisti-

vity semiconductor layers

SOURCE:

Akademiya nauk Litovskoy SSR. Trudy. Seriya B,

no. 1(23), 1962, 73-84

This paper is continuation of the combined investigation of thin layers of cadmium telluride (see Parts I-IV). Diffigation of thin layers of cadmium telluride (see Parts 1-17). Difficulties in measurement of the Hall effect using alternating electric and magnetic fields are discussed. This method has been described and magnetic fields are discussed. This method has been described and magnetic fields are discussed. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29, 1950), by B.R. Russel and C. Jahling (Mev. Sci. Instr., 21, 1028-29

Card 1/3

Combined investigation ...

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instability of the amplification factor of the narrow-band amplifier which is used to select f_R ; 3) appearance of signals with frequencies f_E and f_H at the amplifier input and in the sample giving rise to unwanted signals; 4) high noise level of the Hall probes; 5) shunting action of the stray capacitance of the amplifier input. These and less important difficulties are dealt with briefly and circuit modifications are suggested for their elimination. The maximum sensitivity of the authors' apparatus was limited by the thermal noise of the input impedance and was represented by the carrier mobility (determined from the Hall effect) of 4 x 10-3 cm² = v-1 sec-1 which was obtained for sample resistances up to 10^8 ohm. The apparatus can be used for measurement on samples of up to 10^{12} ohm resistance when the sensitivity falls to 10 cm^2 = v^{-1} sec-1. At all the sample resistances up to 10^{12} ohm the authors' apparatus had a sensitivity higher than that of other apparatus described in literature. There are 6 figures.

ASCOCIATION:

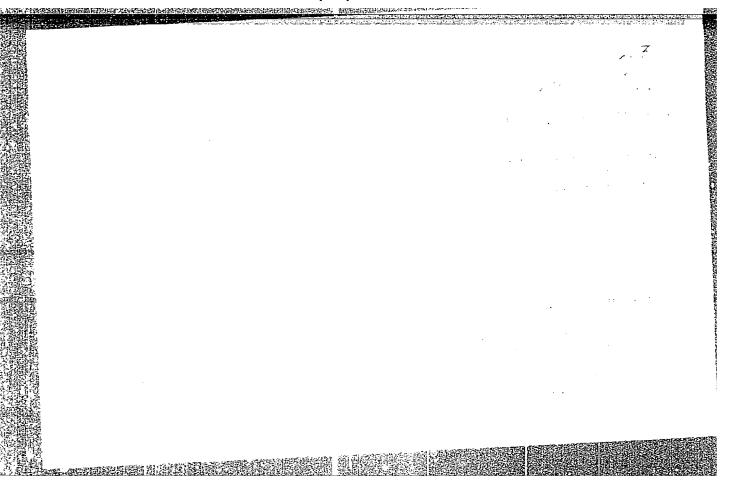
Institut fiziki i matematiki Akademii nauk Litovskoy SSR (Institute of Physics and Mathematics, Academy

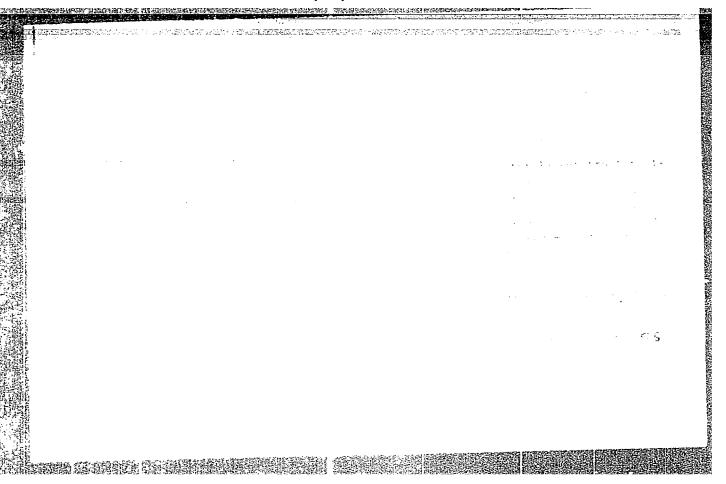
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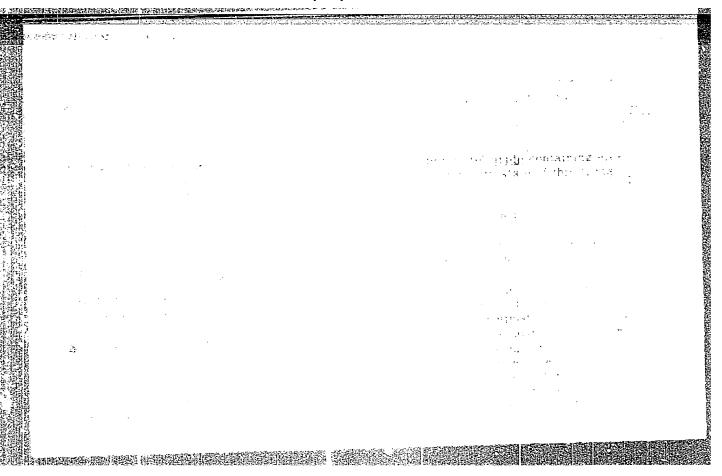
Combined investigation ...

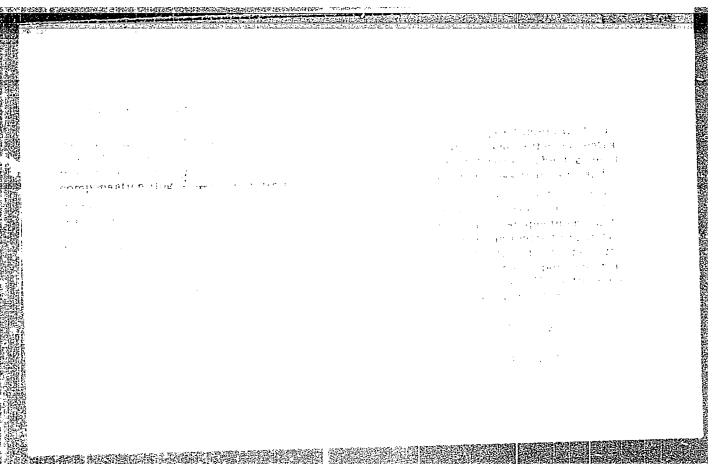
Of Sciences, LithSSR)

SUBMITTED: February 23, 1961

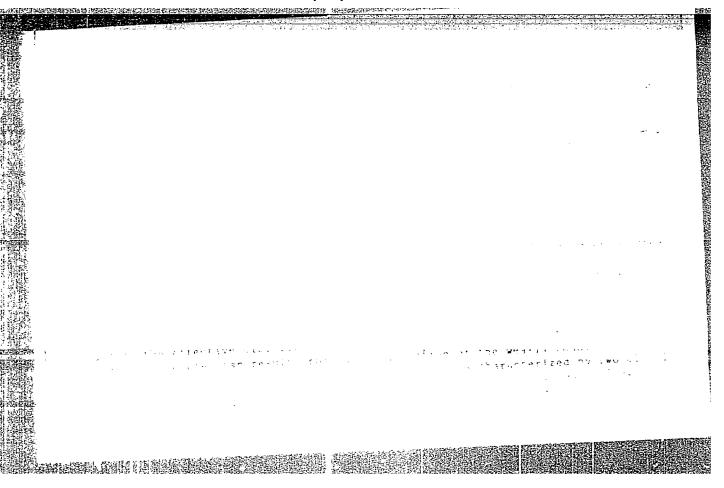


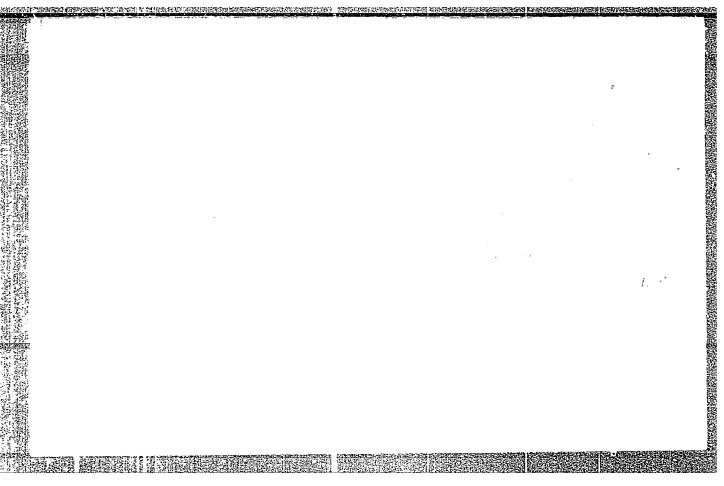






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AUTHOR: Deksnic, A. P. (Deksnys, A.); Tolutis, V. B.; Shimulite, Ya.	
HIND I A. (SIRULY to 6 po)	
Academy of Sciences Lithua-	
nian SSR (Institut riziki i matematika in	-
TITLE: Photoelectric properties of contacts between thin cadmium tel-	
luride films and metals	
SOURCE: AN LitSSR. Litovskiy fizicheskiy sbornik, v. 4, no. 4, 1964,	
519-527	
TOPIC TAGS: cadmium telluride, photosensitivity, gold, silver, copper, bismuth, nickel, antimony, photoelectric property, space charge, photoemf, relaxation process, thin film	
ABSTRACT: Photoelectric properties of contact of a thin CdTe (n) film	
with Au, Ag, Cu, Bi, Sb, and Al acceptal photosensitivity and	
relaxation processes were investigation found to be determined by the	
relaxation processes were investigated. The characteristic termined by the electric phenomena in such contacts were found to be determined by the state of the CdTe(n)-metal interface. The height of the potential barstate of the CdTe(n)-metal interface.	
State of the Cureto, and the cureto will be a superior and the cure of the cur	
Card 1/2	

11926-66 ACC NR: AT50286					8
ier in such a ents in the couctivity portiects of the land (2) the genforeign impurite relaxation by the capacitary the resistant formulas.	ntact may be ons in the s yer) and an eration of c ies in the s processes of	explained pace charg irregular harge carr pace charge the photo	e region (distributiiers by de e region.	due to structon of the imege energy le It was estate contact ar	tural de- purities, vels of blished that e determined er layer and
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	SUBH DATE:	09Jan64/	ORIG REF:	003/ OTH	REF: 000
	SUBH DATE:	09Jan64/	ORIG REF:	003/ OTH	REF: 000
UB CODE: 20/	SUBH DATE:	09Jan64/	ORIG REF:	003/ OTH	REF: 000
	SUBH DATE:	09Jan64/	ORIG REF:	OO3/ OTH	REF: 000

EWT(1)/EWT(m)/FTC(F)/EWG(m)/EWP(t)/EWP(b) IJP(c) RDW/JD 5028693 SOURCE CODE: UR/2910/64/004/004/0497/0507 11925-66_ 63 ACC NR: AT 5028693 AUTHOR: Tolutis, V. B.; Shimulite, Ye. A. (Simulyte, E.) C3+1 ORG: Institute of Physics and Mathematics, Academy of Sciences Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR) TITLE: Electric properties of a film pn junction and of contacts of cadmium telluride thin films with metals of groups I, III, V, and VIII AN LitŠSR. Litovskiy fizicheskiy sbornik, v. 4, no. 4, 1964, SOURCE: 497-507 TOPIC TAGS: pn junction, thin film circuit, cadmium telluride, space charge, impurity level, electric conduction ABSTRACT: The electric properties of contacts of CdTe(n) with Al and In, CdTe(p) with Au, CdTe(n) with Au, Ag, Cu, Sb, Bi, and Ni, and the CdTe(n)-CdTe(p) film pn junction were studied. A study of the potential distribution in longitudinal samples near the electrodes and of properties of transverse systems of the type $H1-CdTe(n)-H_2$ and $H_1-CdTe(n)-H_2$ -CdTe(p) showed that the character of the conduction of such contacts is substantially affected by the state of the surface of CdTe thin films during deposition of the electrode. It is shown that at the surface of Card 1/2

L 11925-66

ACC NR: AT5028693

CdTe(n) films there is usually a substantial potential barrier resulting from a considerable concentration of acceptor levels due to adsorbed foreign molecules, (e. g., oxygen or water) and a surface layer in which the concentration of excess cadmium is much less than in the lower levels of the layer. The absence of a definite dependence of the thickness of the space charge layer on the conductivity of the CdTe(n) thin film, the absence of a definite region of saturation currents in the reverse direction, and the large resistance of the base part of the system are due to a high degree of compensation of the impurity levels in the CdTe(n) thin film. The strong dependence of the currents on the voltage in the reverse direction and their large nominal values are explained by shunting regions of high conductivity in the barrier layer and the generation of carriers by deep impurity levels in the space charge region. Orig. art. has: 13 figures.

SUB CODE: 20/ SUBM DATE: 29Dec63/ ORIG REF: 005/ OTH REF: 003

Card 2/2

EWT(1)/EWT(m)/ETC(F)/EWG(m)/T/EWP(t)/EWP(b)/EWA(h)/EWA(c) IJP(c)
AT5028694 RDW/JD/AT SOURCE CODE: UR/2910/64/004/004/0509/0518 L 11924-66 ACC NR: AUTHOR: Deksnis, A. P. (Deksnys, A.); Tolutis, V. B.; Shimulite, Ye. (Simulyte, E.) 44 ORG: Institute of Physics and Mathematics, Academy of Sciences Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR) 21, 44,56 'pn junction TITLE: Photoelectric properties of a film cadmium telluride SOURCE: AN LitSSR. Litovskiy fizicheskiy sbornik, v. 4, no. 4. 1964. 509-518 TOPIC TAGS: cadmium telluride, photosensitivity, photoelectric property, space charge, relaxation process, photo emf, pn junction, thin film circuit, minority carrier ABSTRACT: The lux ampere, lux volt, and load characteristics as well as the spectral photosensitivity and relaxation processes were studied. It was found that the state of the interface -- in this case the interface between CdTe(n) and CdTe(p)—and the degree of compensation of energy levels in the CdTe film considerably affect the photoelectric phenomena in a CdTe film junction just as in a CdTe(n)-metal contact. It is shown that a prime role in these phenomena is played by processes of generation and recombination of carriers in the space charge region. Card 1/2

L 11924-66 ACC NR AT5028694 The mean lifetime of minority carriers τ_0 is approximately equal to $5\cdot 10^{-10}$ sec, the mean diffusion length L_0 to $6\cdot 3\cdot 10^{-5}$ cm, and the maximum height of the potential barrier does not exceed 0.65 V. The relaxation processes of the photo emf in the film junction are determined by the capacitance and differential resistance of the barrier layer and also by the resistance of the external circuit. Comparison of the characteristics of the film junction with the characteristics of a single crystal photocell reported in the literature shows that the film junctions have greater ballast resistances and poorer photoelectric characteristics in other reports than single crystal junctions, and as a result their efficiency is only one-third that of single crystal cells. Illumination of a film junction with sunlight having an energy flux of 50 mW cm⁻² produced a no-load photo emf of 600 mV, a short circuit current of 2.1 ma cm⁻², and an efficiency of 2.5%. Orig. art. has: 7 figures, 1 table, 21 formulas. OTH REF: 002 ORIG REF: 003/ SUBM DATE: 09Jan64/ SUB CODE: 20/

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

EWT(m)/T/EWP(t)/ETI SOURCE CODE: UR/2910/65/005/003/0377/0386 ACC NR AT6023222 AUTHOR: Deksnis, A. P. -- Deksnys, A.; Paukshte, Yu. A. -- Paukste, J.; Tolutis, V. B. -- Tolutis, V. ORG: Institute of Physics and Mathematics, Academy of Sciences, Lithuanian SSR (Institut fiziki i matematiki Akademiya nauk Litovskoy SSR) TITLE: Characteristics of thin layers of the In-Te system in the region from 60 to 50% Te SOURCE: AN LitSSR. Litovskiy fizicheskiy sbornik. v. 5, no. 3. 1965, 377-386 TOPIC TAGS: indium compound, tellurium compound, semiconducting film, magnetic thin film, PHASE DIAGRANU ABSTRACT: The phase diagram of thin layers of the In-Te system obtained by applying a stoichiometric compound In₂Te₃ by instantaneous vaporization on glass backings, which had a temperature gradient from 450 to 670K during spraying, was investigated. It was established that the phase diagram of such layers in the direction of the temperature gradient can characterize both a continuous cross section of the constitution diagram of the In-Te system in the region from 60 to 50% Te, and that there are three compounds and two transition regions in this phase cross section: the compound In2Te3 with an activation energy at

L 44025-66

ACC NR: AT6023222

290K of 1.10 eV, the compound InTe with a metallic absorption character, and an unknown phase with an activation energy of 1.52 eV. The transition between the unknown phase and the phase $\ln_2 \text{Te}_3$ consists of large phase inclusions of an unknown phase in the $\ln_2 \text{Te}_3$ phase. It was also established that the thin layer of the compound $\ln_2 \text{Te}_3$ is in an unordered state and that the degree of the structural defects of the thin layers of the compound $\ln_2 \text{Te}_3$ rapidly increases with a drop of temperature of the backing when spraying the layer. It is pointed out that the value of the activation energy obtained in this investigation for the compound $\ln_2 \text{Te}_3$ ($\Delta E = 1.10$ eV) is close to the values obtained from electrical and optical investigations. The results of the investigation permit the assertion that the unknown phase really exists as an independent compound. It is difficult to say whether the unknown phase can be identified with the compound $\ln_2 \text{Te}_3$ at present since there is no information about this compound in the literature except for one reference, and other researchers completely ignore the existence of this compound. The answer to this problem can be obtained only by a detailed x-ray structural analysis of this phase. Orig. art. has: 6 figures.

SUB CODE: 11/ SUBM DATE: 01Feb65/ ORIG REF: 003/ OTH REF: 008

Card 2/2 blg

L LL 292-66 EWT(1)/EWT(m)/EWP(t)/ETI IJP(c) JD/JW/JG/GG ACC NR: AT6023223 SOURCE CODE: UR/2910/65/005/003/0387/0393 AUTHOR: Bertulis, K. P.; Tolutis, V. B. ORG: Institute of Physics and Mathematics of the Academy of Sciences of the Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR)
ORG: Institute of Physics and Mathematics of the Academy of Sciences of the Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR)
ORG: Institute of Physics and Mathematics of the Academy of Bereioss Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR)
cerium, and
TITLE: Dielectric properties of thin films of praseodymium, cerium, and neodymium fluorides
SOURCE: AN LitSSR. Litovskiy fizicheskiy sbornik, v. 5, no. 3, 1965, 387-393
TOPIC TAGS: dielectric constant, dielectric property, dielectric loss,
ABSTRACT: The results are presented of an investigation of both the effective dielectric constants (e ₁) and dielectric losses of thin films of praseodymium (PrF ₃) dielectric constants (e ₁) and dielectric losses of thin films of praseodymium (PrF ₃) dielectric constants (e ₁) and dielectric losses of thin films of praseodymium (PrF ₃) dielectric constants (e ₁) and dielectric losses on temperature and frequency may be of e ₂ and the dependence of dielectric losses on temperature and frequency may be
Card 1/2

impurity NdF3 and from the NdF3 se	by the present activation energy of the present of the close dependence of the constant of the	,1 ev. The valu asurements, is to 5,9—6,4 ev. he breakdown fi	layers under the mined to be: for e of the forbidder 4,85 ev, while the The process of eld was determined. [Based on authors of the cold o	e values for F aging; of ed we ed according to ors' abstract]	rF ₃ and as investigated the thickness [AM]	
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ENT(d)/ENT(1)/EEC(k)-2/IIJP(z)SOURCE CODE: UR/2910/65/005/003/0417/0424 AUTHOR: Chesnavichyus, A. A. — Cesnavicius, A.; Alekseyunas, A. A. — Aleksiejonas, A.; Tolutis, V. B. - Tolutis, V. 54 ORG: Institute of Physics and Mathematics, Academy of Sciences Lithuanian SSR (Institut fiziki i matematiki Akademii nauk Litovskoy SSR) TITLE: Impulse-sinusoidal method of measuring the volt-capacitance and volt-ampere characteristics of relaxing p-n-junctions of W SOURCE: AN LitSSR. Litovskiy fizicheskiy sbornik. v. 5, no. 3. 1965, 417-424 TOPIC TAGS: volt ampere characteristic, electric capacitance, capacitance bridge, pn junction ABSTRACT: A bridge method operating under impulse-sinusoidal conditions is proposed for the simultaneous measurement of the barrier capacitance and static and base resistances of relaxing p-n-junctions, i.e., junctions with time-dependent parameters. Calculations of the errors and the results of an experimental check of the correctness of the method are given. A special feature of the proposed method is that a square pulse with a peak modulated by a variable voltage is sent to the input of the bridge used for the measurements. This bridge is balanced both with respect to the variable and constant components of the supply voltage. This method of measurement has the advantage that the three electrical parameters of the p-n-junction can be measured simultaneously. To check the proper operation of the bridge, the volt-capacitance and volt-ampere characteristics of selenium rectifiers were measured under pulsed and Card 1/2

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ACC NR: AT6023227	<i>O</i> ;
direct current conditions. The discrepancy of the results obtained under these tions is attributed to the specimens being heated by the current, which is continued by the shape of the volt-ampere characteristic recorded under these conditions by the shape of the volt-ampere characteristic recorded under these conditions is concluded that this method permits studying the volt-capacitance and volt-archaracteristics of relaxing p-n-junctions with relatively large base resistance characteristics of relaxing p-n-junctions with relatively large base resistance measurement error not exceeding 1%. Orig. art. has: 8 figures and 8 formulas	spere to the second sec
SUB CODE: 09/ SUBM DATE: 12Jan65/ ORIG REF: 006/ OTH REF: 003	
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70	
Card 2/2	

ACC NR. AR7000835

SOURCE CODE: UR/0058/66/000/009/A047/A047

AUTHOR: Tolutis, V. B.; Yasutis, V. V.

TITLE: Effect of substrate temperature on the macro- and microstructure of thin cadmium telluride film

SOURCE: Ref. zh. Fizika, Abs. 9A400

REF SOURCE: Lit. fiz. sb., v. 5, no. 4, 1965, 495-502

TOPIC TAGS: cadmium telluride, thin film, than film entresstructure, than film, macrostructure, substrate temperature, thingthe structure, the mochanism, polycrystalline film, hit temperature effect

ABSTRACT: A study was made of the parameters of the macro- and microstructure of sputtered thin CdTe film as a function of substrate temperature (T_n) within the 120-245C range. Two substantially different structural regions, separated by a narrow transitional area with the point of separation at $T_n \approx 185C$, were identified in the film on the basis of several factors: the nature of the relationship between the parameters of the distribution curve for the area of the film's visible structure in relation to the grain size of the crystals (maximum distribution func-

Card 1/2

ACC NRI AR7000835

tion values, distribution curve half-widths), the mean crystal grain area values, the effective CdTe accommodation coefficient, the texture parameters, and the correlation between the cubic and hexagonal phases of the film as a function of T_n . It was found that the causes of such a sharp demarcation in the structure of the film as a function of T_n are the conditions for the condensation of T_n , which determine the mechanism of the growth of the CdTe layer as a whole. A model of the mechanism of the growth of the CdTe film is given. [Translation of abstract]

SUB CODE: 20/

Card 2/2

BLESTKINA, T.G.; TOLUZAKOV, V.L.

Unusual case of esophageal cancer combined with chronic myeloid leukemia. Vop.onk. 9 no.2:101 - 103 '63. (MINA 16:9)

1. Iz khirurgicheskoy kliniki usovershenstvovaniya vrachey
no.l Voyenno-meditsinskoy ordena Lenina Akademii imeni S.M.
Kirova (nachal'nik kliniki - deystvitel'nyy chlen AMN SSSR
Kirova (nachal'nik kliniki - deystvitel'nyy chlen AMN SSSR
prof. general - leytenant meditsinskoy sluzhby P.A.Kupriyanov).
(ESOPHAGUS—CANCER) (LEUKEMIA)
(MARROW—DISEASES)

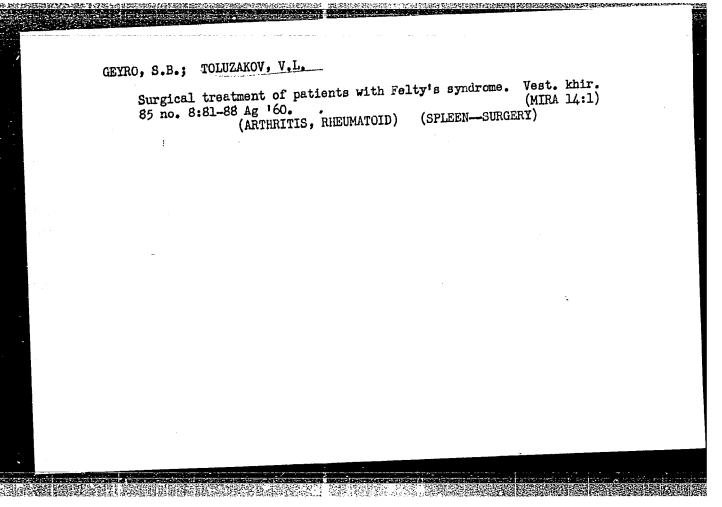
GEYRO, S.B., kand.med.nauk; TOLUZAKOV, V.L., kand.med.nauk

Felty's syndrome; clinical aspects, pathogenesis, therapy. Terap.

(MIRA 13:3)

arkh. 31 no.10:76-81 0 59.

1. Iz kliniki 1-y fakul'tetskoy terapii (nachal'nik - prof. V.A.
Beyer) i kliniki khirurgii usovershenstvovaniya vrachey (nachal'nik deystvitel'nyy chlen AMN SSSR prof. P.A. Kupriyanov) Voyenno-meditsinskoy ordena Lenina akademii imeni S.M. Kirova.
(ARTHRITIS, RHEUMATOID)



KOLESOV, A.P.; KUTUSHEV, F.Kh.; TOLUZAKOV, V.L.; BURMISTROV, M.L.; SHABLIY, T.P.

Operability and the immediate outcome of surgical treatment of lung cancer. Vop.enk. 11 no.11;22..26 '65. (MIRA 19:1)

l. Iz khirurgicheskoy kliniki dlya usovershenstvovaniya vrachey No.l (nachal nik - prof. A.P. Kolesov) Voyenno-meditsinskoy ordena Lenina akademii imeni S.M.Kirova.

TOLUZAKOV, V.L. (Leningrad, K-9, ul. Smirnova, d.8, kv.53); KROL, Ya.M.; DAVYDENKO, V.A.; BONK, G.M.

So-called cavitary form of pulmonary cancer. Vop. onk. 10 no.5: (MIRA 18:8)

1. Iz khirurgicheskoy kliniki dlya usovershenstvovaniya vrachey No.1 Voyenno-meditsinskoy akademii imeni Kirova (nachal'nik - prof. A.P.Kolesov).

TOLUZAROV, Tala; DAVIDENTO, V.A., KROL, Ya.M.; BONK, G.M.

Reseasenelogical evidences of the inoperability of pulmonary cancer. Vop. onk. 11 no.7:9-17 '65. (MIHA 18:9)

l. Iz knirurgicheskoy kliniki dyla usovershonstvovaniya vrachey No.l Voyenno-meditsinskoy ordena Lenina akademii imeni S.M. Kirova (nachal'nik - prof. A.P. Kolesov).

KRASNOROGOV, B.V.; TOLUZAKOV, V.L.

- Diagnostic errors in lung cancer. Vop.onk. 9 no.2:11-16'63. (MIRA 16:9)

l. Iz khirurgicheskoy kliniki usovershenstvovaniya vrachey no.l. (nachal'nik - deystvitel'nyy chlen AMN SSSR prof. P.A.Kupriyanov) Voyenno-meditsinskoy ordena Lenina Akademii imeni S.M. Kirova. (LUNGS-CANCER)

KUPRIYANOV, P.A., prof.; BLESTKINA, T.G.; IZBINSKIY, A.L., dotsent; TOLUZAKOV, V.L., kend.med.nauk; SHANIN, Yu.N., kend.med.nauk

Postoperative period in patients with acquired heart defects.

(MIRA 15:11)

Khirurgiia no.1:23-30 62.

1. Iz khirurgicheskoy kliniki dlya usovershenstvovaniya vrachey
No.l (nach. - deystvitel'nyy chlen AMN SSSR prof. P.A. Kupriyanov)
Voyenno-meditsinskoy ordena Ienina akademii imeni S.M. Kirova.

(HEART-SURGERY)

DESCRIPTION OF THE PROPERTY OF

UVAROV, B.S., TOLUZAKOV, V.L., kand.med.nauk

Potentiated anesthesia in major surgery. Hov.khir.erkh. no.1:3-10
[MIRA 11:11]

1. Khirurgicheskaya klinika usovershenstvovaniya vrachey (nachal'nik prof. P.A. Kupriyanov) Voeynno-meditsinskoy akademii imeni S.M. Kirova. Adres avtorov: Leningrad, pr. K. Marksa, d.5/6, klinika khirurgii Instituta dlya usoverhsenstvovaniya vrachey Voyenno-meditsinskoy akademii imeni S.M. Kirova.

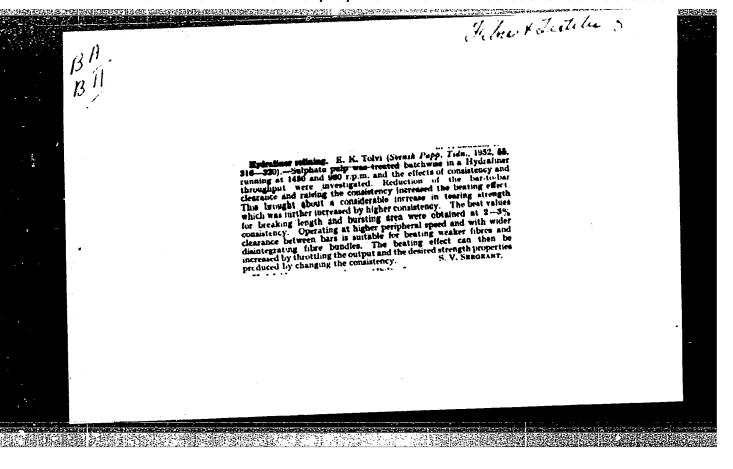
(ANESTHESIA)

GEYRO, S. B., dotsent; TOLUZAKOV, V. L., kand. med. nauk; DYGIN, V. P. (Leningrad)

Splenectomy in autoimmune diseases of the blood system. Klin. med. (MIRA 14:12) no.6:62-69 '61.

1. Iz kliniki fakul tetskoy terapii (nach. - prof. V. A. Beyer) i kliniki khirurgii dlya usovershenstvovaniya vrachey (nach. - deystvitel nyy chlen AMN SSSR prof. P. A. Kupriyanov) Voyennomeditsinskoy ordena Lenina akademii imeni S. M. Kirova.

(SPLEEN_SURGERY) (BLOOD_DISEASES)



TOLVINSKAYA, A. V.

Tolvinskaya, A. V.

"The Surface Resistance of Solid Dielectrics." Min Higher Education USSR.
Leningrad Polytechnic Inst imeni M. I. Kalinin. Leningrad, 1955 (Dissertation for the degree of Candidate in Technical Sciences)

SO: Knizhnaya letopis' No. 27, 2 July 1955

BRZHEZANSKIY, V.I., inzh.; VAKSER, N.M., inzh.; PETROVA, K.N., inzh.;

TOLVINSKAYA, A.V., kand.tekhn.nauk

Dependence of the electrical properties of mica plastics on the
initial raw materials. Vest. elektroprom. 34 no.5:9-11 My '63.

(MIRA 16:5)

(Mica-Electric properties) (Plastics-Electric properties)

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

ACC NR: AT6022764 (A) SOURCE CODE: UR/2563/65/000/258/0138/0141

AUTHOR: Brzhezanskiy, V. I.; Vakser, N. M.; Tolvinskaya, A. V.

ORG: none

TITLE: Mica plastics

SOURCE: Leningrad. Politekhnicheskiy institut. Trudy, no. 258, 1965.

Vysokovol'tnaya izolyatsiya liniy i apparatov (High voltage insulation of lines and

apparatus), 138-141

TOPIC TAGS: mica product, mica plastic mica

ABSTRACT: The mica plastic consists of small phlogopite flakes bonded by aluminum phosphate (Soviet trademark AF-2,5) or silicone. Developed by the Department of Electric Insulation, Cables, and Capacitors, LPI, the new material is intended as insulation operating at 350-400C in electrical equipment. Within 25-400C, the mica plastic has tgo from about 0.04 to about 0.25 and & about 6 or 7 measured at 1000 cps. Although good electrical characteristics were ensured

Card 1/2

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

EWP(e)/EWI(m) SOURCE CODE: UR/0143/66/000/004/0025/0029 ACC NR: AF6023674 AUTHOR: Brzhezanskiy, V. I. (Engineer); Vakser, N. M. (Engineer); Tolvinskaya, A. V. (Engineer) ORG: Leningrad Polytechnic Institute im. M. I. Kalinin (Leningradskiy politekhnicheskiy institut) TITLE: Comparison of the properties of sheet mica made from muscovite, phlogopite, and vermiculite Energetika, no. 4, 1966, 25-29 SOURCE: IVUZ. dielectric property TOPIC TAGS: mica, ABSTRACT: All mica test samples were prepared with the same binder, that is, with Type K-47 organosilicon lacquer, used in the amount of 4% with respect to the dry sample. All the samples were baked under the same conditions: 300°C, pressure 40 kg/cm, for 5 hours. Measurements of the tangent of the dielectric losses and dielectric permeability were made at a frequency of 1 kilocycle. The results of the tests are shown in a series of curves. The best electrical properties and the least dependence of these properties on temperature were found for sheet mica made from muscovite; on heating this sheet mica from 22 to 600°C, the UDC: 621.315.613.1 Card 1/2

APPROVED FOR RELEASE: 07/16/2001 CIA-RDP86-00513R001756130001-7"

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ACC NR: AP6023674

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tangent of the dielectric losses rose from 0.017 to 0.11; the specific volumetric resistance decreased from 5.8 x 10¹³ to 7.8 x 10¹¹ ohm-cm; the dielectric permeability rose from 3.4 to 3.7; the electric strength decreased from 27 kilovolts/mm to 22 kilovolts/mm. In sheet mica made from phlogopite, values of the properties of the same order were observed at a temperature of 350°C, as compared with 600°C for the sheet mica made of muscovite. Thus, sheet mica made of muscovite with K-47 lacquer can be used up to 500°C, if at this temperature there is required an electrical strength of the order of 20 kilovolts/mm. Above 500°C, water of crystallization begins to separate out, which leads to a change in the properties of this sheet mica at higher temperatures. Sheet mica made of phlogopite can be used up to 350°C; above this temperature, there is a sharp rise in the tangent of the dielectric losses. Sheet mica made of vermiculite can be used only up to 250°C, for the same reason. In general, the muscovite sheet mica is considered the best fer most applications. Orig. art. has: 6 figures.

SUB CODE: 08 / SUBM DATE: OhDec64/ ORIG REF: 001

Card 2/2 LL

65082 6958/ SOV/112-59-22-45361

Translation from: Referativnyy zhurnal, Elektrotekhnika, 1959, Nr 22, pp 9-10 (USSR)

24-7700 AUTHOR:

Tolvinskaya, A.V.

TITLE:

The Influence of the Contact Wetting Angle and Hardness of the Dielectric

on Its Surface Resistance

PERIODICAL:

Nauchno-tekhn. inform. buyl. Leningr. politekhn. in-t, 1958, Nr 7,

pp 16 - 21

ABSTRACT:

The specific surface resistance ho_s of dielectrics depends to a great extent on the humidity of the surrounding air. For different dielectrics

this dependence is different, which is explained by the different

wettability of dielectrics, determined by the contact wetting angle. When the contact wetting angle is determined, it can be said beforehand,

whether ho_s will decrease with an increase in the relative humidity of the surrounding air. Inorganic dielectrics have a smaller contact wetting angle and consequently their ho_s must noticeably decrease with an increase in the relative humidity. The value of ρ_s of organic dielectrics having

a greater contact wetting angle, must change less than that of inorganic dielectrics. From the value of the contact wetting angle it can be merely

Card 1/4

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SOV/112-59-22-45361

The Influence of the Contact Wetting Angle and Hardness of the Dielectric on Its Surface Resistance

said, whether the value of ho_s will change, but nothing can be said about the magnitude of this change, as this depends on the presence of water-soluble substances in the dielectric composition. It is established by experiment; that the decrease in 9 takes place on account of adsorption of water vapor by the surface of a solid dielectric with the result that a polymolecular moisture film forms on the surface of the dielectric. When a gas or vapor comes in contact with a solid matter, either a weak interaction between molecules of the solid matter and gas, or a strong interaction of the type of a chemical reaction can be observed. The first phenomenon is called physical adsorption, and the second chemical sorption or activated adsorption. The value of the contact wetting angle depends on the hardness of the matter. In the table the values of the contact wetting angle (in angular degrees), Moos hardness and ρ_s of some solid dielectrics at a relative humidity of the surrounding air of 0 and 98% are given. The hardness is determined by the simplest method (Moos scale). The given data confirm the direct relation between the hardness and the contact wetting angle as they both express the magnitude of the surface energy of a solid dielectric. With an increase in the relative humidity, ρ_s decreases in proportion to the hardness and in inverse proportion

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to the contact wetting angle. Glass and mica are exceptions, which is explained by the presence of water-soluble substances in their composition and by the peculiarities in the

Dielectric	Hardness	Contact angle of wetting	9 _s (Ohm) at humidity	
			0%	98%
Fused quartz Alkali glass Mica Ultra porcelain Aminoplast Folymethylmethacrylate Plastic K-211-34 Polystyrene 6 Cable polyethylene	7 5-6 2 4-5 3 2-3 2.5 2	29 30 50 65 73 86 98	1·10 ¹⁷ 3·10 ¹³ 2·10 ¹⁴ 1·10 ¹⁶ 6·10 ¹⁴ 5·10 ¹⁵ 7·10 ¹⁵ 5·10 ¹⁷ 2·10 ¹⁷	6.5·10 ¹⁰ 5·108 5·109 1·10 ¹³ 3·10 ¹³ 1.5·10 ¹⁵ 7·10 ¹⁴ 3·10 ¹⁵

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The Influence of the Contact Wetting Angle and Hardness of the Dielectric on Its

Dielectric	Hardness	Contact angle of wetting	L S	(Ohm) at
Paraffin Fluoroplast-4 6	1	105 113	0% 6·10 ¹⁶ 5·10 ¹⁷	98% 2 ·10 ¹⁶ 5 ·10 ¹⁷

Three references. See also Referativnyy zhurmal, Elektrotekhnika, 1956, Nr 92.

4

A.O.M.

Card 4/4

MIKHAYLOV, Mikhail Mikhaylovich, prof., doktor tekhn.nauk. Prinimali
uchastiye: ALWKSAHDROVA, L. I., kand.tekhn.nauk; TOLVINSKAIA, A.V.,
kand.tekhn.nauk; IVASHCHRINKO, S.A., kand.tekhn.nauk; MELEKT'IEVA,
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Synchronous compensators for long-distance power lines.
Elektrichestvo no.10:43-47 0 58. (MIRA 12:1)

1. Leningradskiy politekhnicheskiy institut im. Kalinina (for Vazhnov, Tolvinskaya). 2. Nauchno-issledovatel'skiy institut postoyannogo toka (for Gordon). 3. Institut elektromekhaniki AN SSSR (for Zavalishin, Glebov).

(Electric power distribution)

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AUTHORS:

1) Vazhnov, A. I., Docent, Candidate of SOV/105-58-10-10/28 Technical Sciences, Tolvinskaya, Ye. V., Engineer (a woman),

2) Gordon, I. A., Engineer,

3) Zavalishin, D. A., Professor, Doctor of Technical Sciences, Glebov, I. A., Docent, Candidate of Technical Sciences

TITLE:

Synchronous Condensers for Long-Distance Transmission Systems (Sinkhronnyye kompensatory dlya dal'nikh elektroperedach)

PERIODICAL:

Elektrichestvo, 1958, Nr 10, pp 43 - 47 (USSR)

ABSTRACT:

This is a study of problems of design of synchronous condensers connected with the elimination of self-excitation of such generators in various modes of operation. Inasmuch the investigation of two boundary cases of damper system design is of interest, that is to say, of a normal design and of a connected type of winding, this paper is limited to compensators with

salient poles with only one type of rotor. The computations presented in this paper demonstrate that non-compensated supporting condensers, which are intended for continuous duty at rated power with lagging current can be built on

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Synchronous Condensers for Long-Distance Transmission SOY/105-58-10-10/28 Systems

the basis of conventional machines with very high power (75 MVA). In order to be able to obtain a considerable output with leading current, the compensator must operate with negative excitation currents. 2) A supporting synchronous condenser which is compensated for capacity can be designed on the basis of normal condensers. 3) Compensated supporting condensers can be continuously operated ar rated power with lagging and with leading current. 4) In order to guarantee a forced excitation of non-compensated supporting synchronous condensers an increased ceiling voltage of excitation is required. In compensated condensers a similar behaviour is guaranteed by normal exciters. There are 4 figures, 2 tables, and 5 references, 4 of which are Soviet.

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Synchronous Condensers for Long-Distance Transmission S07/105-38-10-10/28 Systems

ASSOCIATION: 1)Leningradskiy politekhnicheskiy institut imeni Kalinina

(Leningrad Polytechnical Institute imeni Kalinin)

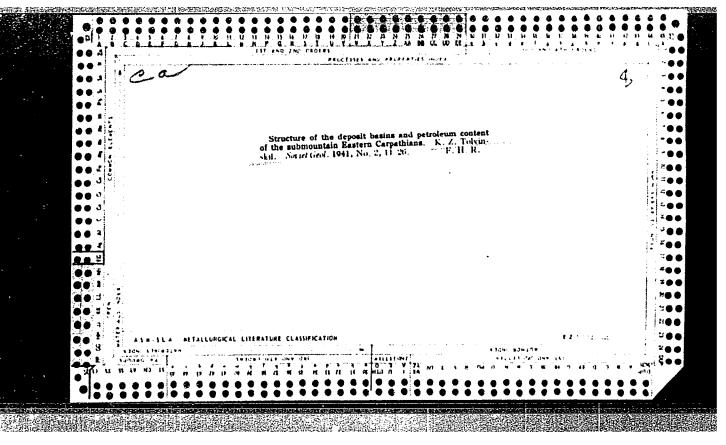
2) Nauchno-issledovatel skiy institut postoyannogo toka

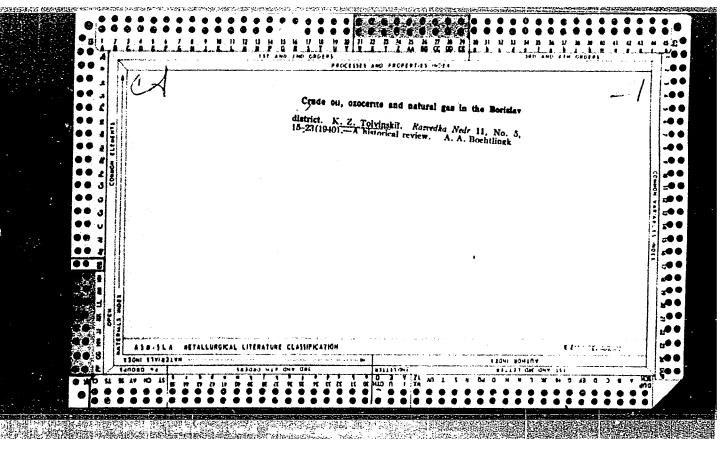
(Scientific Research Institute of Direct Current)
3) Institut elektromekhaniki Akademii nauk SSSR (Institute

of Electromechanics, AS USSR)

SUBMITTED: May 4, 1958

Card 3/3





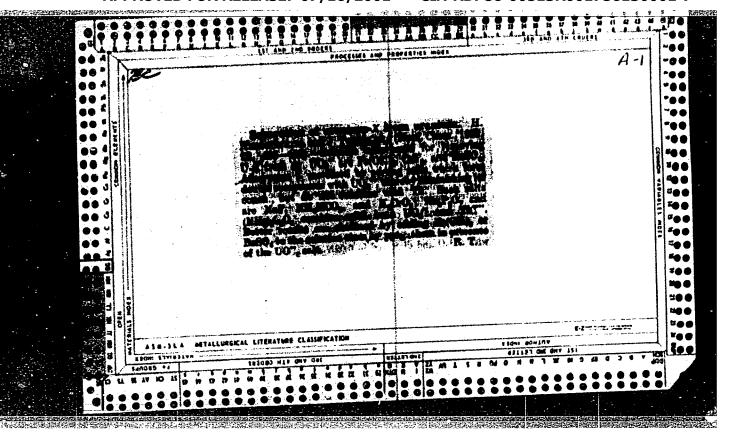
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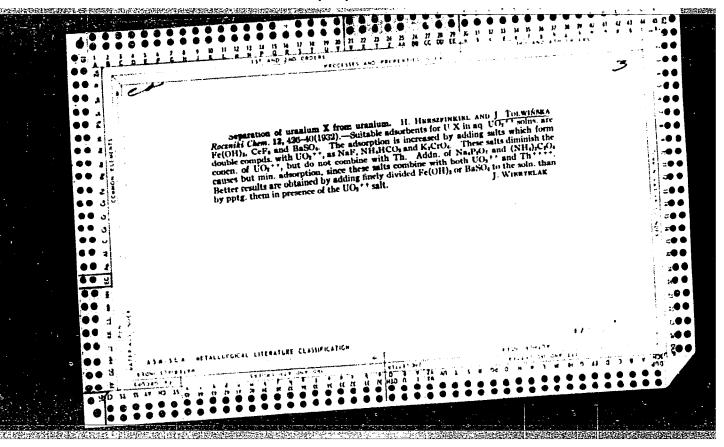
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TOLVINSKIY. V. A.	directed studies on long-distance p transmission by dc and ac at the Pc transmission by dc and ac at the Pc Inst, Acad Sci Uzbek SSR. Shchedri Inst, Acad Sci Uzbek SSR. Shchedri member of the Permanent Commission member of the Permanent Commission Circuit Currents, Min of Rice Power the Commission on Long-Distance Power the Commission on Long-Distance Power and Sci Member 1 and Sci Res of the Sci Council of the Sci Res	ersonal	io 1, p 92 Lished more	Shchedrin (of Scientil A, A, Gorev elen, B, A, F, Fazylov, S, I, Shabad	USSR/Electricity - Personalities
20111.6	ac at the Power Eng ac at the Power Eng SR. Shchedrin is a t Commission on Short- of Ricc Power Stations C-Distance Power Trans- E-Distance Fower Trans- Sci. Acad Sci USSR, and the Sci Res Inst of DC.	Recently, he has for and has 201716	30 scie	His 60th Birth- ic and Pedagog- v, V. A. Tolvin- Alimov, N. I. G. R. Rakhimov, ash	es Jan 52





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